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values, an algorithm is used which from the measured values and the amount of interference calculates whether the reflection profile is sufficiently free of interference that adequate measurement accuracy is achieved.

2. The method of claim 1, characterized in that the algorithm comprises the following steps:

5 V) if the amount of interference exceeds a predetermined threshold, the scanning frequency (f_A) and the pulse repetition frequency (f_{prf}) are varied;

VI) the amount of interference is determined and assessed again;

VII) steps V) and VI) are repeated until the amount of interference is below the predetermined threshold.

5 3. The method of claim 2, characterized in that the variation in the scanning frequency (f_A) and the pulse repetition frequency (f_{prf}) is made on the basis of a predetermined table which contains suitable frequencies, the access to the table to being linear or random.

4. The method of claim 3, characterized in that for changing the scanning frequency (f_A) and the pulse repetition frequency (f_{prf}), the frequencies are selected from a frequency range.

5. The method of one of the foregoing claims, characterized in that the pulse repetition frequency (f_{prf}) is varied by means of a voltage controlled or numerically controlled oscillator (VCO or NCO).

6. The method of claim 5, characterized in that the scanning trigger signal (X_{TA}) is obtained from the transmission trigger signal (X_{TS}) by means of a controllable delay circuit (11), and the delay circuit (11) is supplied with a reference signal (X_S) or (X_{TS}) at the pulse repetition frequency (f_{prf}), and the delay circuit (11) generates an output signal (X_A and X_{TA}), and the delay in the output signal (X_A , X_{TA}) is determined by a predeterminable set-point delay value, with which the delay circuit (11) is controlled.

7. The method of one of the foregoing claims, characterized in that the amount of interference is obtained by a comparison of the pulse, created by the reflection at the boundary layer, with a predetermined reference pulse.

8. The method of one of the foregoing claims, characterized in that the amount of interference is obtained by means of the difference between the maximum and minimum deviation in the reflection profile from a predetermined value or from the reference profile in a predetermined time slot or spacing slot.

9. The method of one of claims 1 or 2, characterized in that the frequency and/or phase of the scanning pulses (X_A) upon a variation in the pulse repetition frequency (f_{prf}) is adapted such that the difference between the scanning frequency and the pulse repetition frequency does not exceed a predetermined range or is constant.

10. A method for increasing the interference resistance of a time domain reflectometer, in particular to high-frequency radiation, in which at a pulse repetition frequency (f_{prf}) a transmission pulse (X_S) is generated and

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5 coupled into a waveguide (4), whose upper end toward the
process terminal is disposed on a holder part (18), and the
signal (X_{probe}), reflected back by a reflector (14), which is
in contact with the waveguide (4), and returning on the
waveguide (4) is scanned for time-expanded display as a
10 reflection profile with scanning pulses (X_A), which are
repeated at a scanning frequency (f_A), and from the
reflection profiles, measured values are continuously
obtained that contain the distance of the reflector (14) to
the process terminal, having the following algorithm for
15 deciding on the usability of the measured values;

I) varying the scanning frequency (f_A) and the pulse
repetition frequency (f_{prf}), and either

II.1) the time-expanded display of the reflection
profile remains unchanged, or

20 II.2) if there is a change over time in the reflection
profile, the change in the time expansion is known and is
taken into account in the evaluation of the profile;

III) determining the amount of interference and
obtaining the measured value from the measurement of the
25 reflection profile or of a part thereof;

IV) checking the usability of the measured value by
evaluating the amount of interference, and continuing with
step I.

11. The method of claim 10, characterized in that the
algorithm has the following further steps:

14. The circuit arrangement of claim 12 or 13, characterized in that the trigger generator (1) includes a controllable delay circuit (11), which is subjected to the output signal of the controlled oscillator (10), and whose output signal represents the scanning trigger signal (X_{TA}).

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15. The circuit arrangement of claim 13 or 14, characterized in that the trigger generator (1) includes not only the controlled oscillator (10, CO), which oscillates at the pulse repetition frequency (f_{prf}), but also a further controlled oscillator (CO), which oscillates at the scanning frequency (f_A), and optionally the difference in frequencies is set to a predetermined value with a regulator and kept constant.

16. The circuit arrangement of claim 15, characterized in that the oscillators are embodied as an oscillator bank, in order to furnish a constant frequency difference between the pulse repetition frequency (f_{prf}) and the scanning frequency (f_A).